## Shifan Gao

## List of Publications by Year in descending order

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2258059 2272923 11 73 3 4 citations h-index g-index papers 11 11 11 82 citing authors docs citations times ranked all docs

| #  | Article   | IF  | CITATIONS |
|----|---|-----|-----------|
| 1  | Rapid and Quantitative Analysis of Exosomes by a Chemiluminescence Immunoassay Using Superparamagnetic Iron Oxide Particles. Journal of Biomedical Nanotechnology, 2019, 15, 1792-1800.                       | 1.1 | 23        |
| 2  | Programmable Linear RAM: A New Flash Memory-based Memristor for Artificial Synapses and Its Application to Speech Recognition System. , 2019, , .   |     | 11        |
| 3  | MRAM Acceleration Core for Vector Matrix Multiplication and XNOR-Binarized Neural Network Inference. , 2020, , .  |     | 9         |
| 4  | Improvement of Ferroelectricity and Reliability in Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> Thin Films With Two-Step Oxygen Vacancy Engineering. IEEE Electron Device Letters, 2022, 43, 1057-1060. | 3.9 | 8         |
| 5  | An Euler–Lagrange Equation Oriented Solution for Write Energy Minimization of STT-MRAM. IEEE<br>Transactions on Electron Devices, 2019, 66, 3686-3689.  | 3.0 | 5         |
| 6  | Neural Network Acceleration and Voice Recognition with a Flash-based In-Memory Computing SoC. , 2021, , .   |     | 5         |
| 7  | A Compute-in-Memory Architecture Compatible with 3D NAND Flash that Parallelly Activates Multi-Layers. , 2021, , .  |     | 4         |
| 8  | Probing Write Error Rate and Random Telegraph Noise of MgO Based Magnetic Tunnel Juction Using a High Throughput Characterization System. , $2019$ , , .  |     | 3         |
| 9  | Superior Data Retention of Programmable Linear RAM (PLRAM) for Compute-in-Memory Application. , 2020, , .   |     | 3         |
| 10 | Systematic Study of Medium States in Spin-Transfer Torque Magnetoresistance Random Access Memory and Their Implication for the Bit Error Rate. IEEE Electron Device Letters, 2020, 41, 557-560.               | 3.9 | 2         |
| 11 | High-efficiency array-level MRAM parameters extraction with the device-in-series test structure.<br>Journal of Applied Physics, 2022, 131, .  | 2.5 | 0         |